

OP27A/C/E/G, OP37A/C/E/G

Low-Noise High-Speed Precision Operational Amplifier

The OP27 and OP37 operational amplifiers combine outstanding noise performance with excellent precision and high-speed specifications. The wideband noise is only 3 nV/√Hz and with the 1/f noise corner at 2.7 Hz, low noise is maintained for all low-frequency applications.

The outstanding characteristics of the OP27 and OP37 make these devices excellent choices for low-noise amplifier applications requiring precision performance and reliability. Additionally, the OP37 is free of latch-up in high-gain, large-capacitive-feedback configurations.

Rochester Electronics Manufactured Components

Rochester branded components are manufactured using either die/wafers purchased from the original suppliers or Rochester wafers recreated from the original IP. All recreations are done with the approval of the OCM.

Parts are tested using original factory test programs or Rochester developed test solutions to guarantee product meets or exceeds the OCM data sheet.

Quality Overview

- ISO-9001
- AS9120 certification
- Qualified Manufacturers List (QML) MIL-PRF-38535
 - Class Q Military
 - Class V Space Level
- Qualified Suppliers List of Distributors (QSLD)
 - Rochester is a critical supplier to DLA and meets all industry and DLA standards.

Rochester Electronics, LLC is committed to supplying products that satisfy customer expectations for quality and are equal to those originally supplied by industry manufacturers.

The original manufacturer's datasheet accompanying this document reflects the performance and specifications of the Rochester manufactured version of this device. Rochester Electronics guarantees the performance of its semiconductor products to the original OEM specifications. 'Typical' values are for reference purposes only. Certain minimum or maximum ratings may be based on product characterization, design, simulation, or sample testing.

 Direct Replacements for PMI and LTC OP27 and OP37 Series

Features of OP27A, OP27C, OP37A, and OP37C:

- Maximum Equivalent Input Noise Voltage:
 3.8 nV/√Hz at 1 kHz
 5.5 nV/√Hz at 10 kHz
- Very Low Peak-to-Peak Noise Voltage at 0.1 Hz to 10 Hz ... 80 nV Typ
- Low Input Offset Voltage . . . 25 μV Max
- High Voltage Amplification ...1 V/μV Min

Feature of OP37 Series:

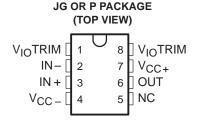
Minimum Slew Rate . . . 11 V/μs

description

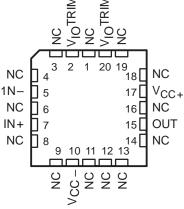
The OP27 and OP37 operational amplifiers combine outstanding noise performance with excellent precision and high-speed specifications. The wideband noise is only 3 nV/ $\sqrt{\text{Hz}}$ and with the 1/f noise corner at 2.7 Hz, low noise is maintained for all low-frequency applications.

The outstanding characteristics of the OP27 and OP37 make these devices excellent choices for low-noise amplifier applications requiring precision performance and reliability. Additionally, the OP37 is free of latch-up in high-gain, large-capacitive-feedback configurations.

The OP27 series is compensated for unity gain. The OP37 series is decompensated for increased bandwidth and slew rate and is stable down to a gain of 5.

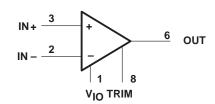


FK PACKAGE (TOP VIEW)



NC - No internal connection

symbol



Pin numbers are for the JG and P packages.

The OP27A, OP27C, OP37A, and OP37C are characterized for operation over the full military temperature range of -55° C to 125° C. The OP27E, OP27G, OP37E, and OP37G are characterized for operation from -25° C to 85° C.

AVAILABLE OPTIONS

	Viemov	STABLE		PACKAGE	
TA	V _{IO} max AT 25°C	GAIN	CERAMIC DIP (JG)	CHIP CARRIER (FK)	PLASTIC DIP (P)
	25\/	1	_	_	OP27EP
-25°C to 85°C	25 μV	5	_	_	OP37EP
-25°C 10 65°C	100 μV	1	_	_	OP27GP
	100 μν	5	_	_	OP37GP
	25 μV	1	OP27AJG	OP27AFK	_
-55°C to 125°C	25 μν	5	OP37AJG OP37AFK		_
-55 C to 125 C	100 μV	1	OP27CJG	_	_
	100 μν	5	OP37CJG	_	_

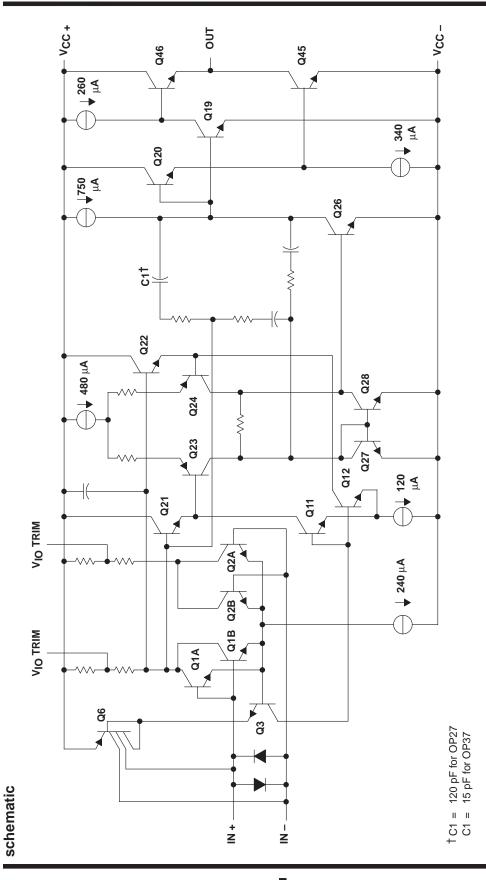


Please be aware that an important notice concerning availability, standard warranty, and use in critical applications of Texas Instruments semiconductor products and disclaimers thereto appears at the end of this data sheet.



Template Release Date: 7–11–94

OP27A, OP27C, OP27E, OP27G OP37A, OP37C, OP37E, OP37G LOW-NOISE HIGH-SPEED PRECISION OPERATIONAL-AMPLIFIER SLOS100C - FEBRUARY 1989 - REVISED SEPTEMBER 2000





OP27A, OP27C, OP27E, OP27G OP37A, OP37C, OP37E, OP37G LOW-NOISE HIGH-SPEED PRECISION OPERATIONAL-AMPLIFIER

SLOS100C - FEBRUARY 1989 - REVISED SEPTEMBER 2000

absolute maximum ratings over operating free-air temperature range (unless otherwise noted)

Supply voltage, V _{CC+} (see Note 1)	S
Supply voltage, V _{CC} (see Note 1) – 22 V	
Input voltage, V _I	In
Duration of output short circuit unlimited	D
Differential input current (see Note 2) ±25 mA	D
Continuous power dissipation See Dissipation Rating Table	
Operating free-air temperature range: OP27A, OP27C, OP37A, OP37C – 55°C to 125°C	0
OP27E, OP27G, OP37E, OP37G – 25°C to 85°C	
Storage temperature range – 65°C to 150°C	
Lead temperature 1,6 mm (1/16 inch) from case for 60 seconds: JG or FK package	
Lead temperature 1,6 mm (1/16 inch) from case for 10 seconds: P package	Le

NOTES: 1. All voltage values are with respect to the midpoint between V_{CC+} and V_{CC-} unless otherwise noted.

The inputs are protected by back-to-back diodes. Current-limiting resistors are not used in order to achieve low noise. Excessive
input current will flow if a differential input voltage in excess of approximately ± 0.7 V is applied between the inputs unless some
limiting resistance is used.

DISSIPATION RATING TABLE

PACKAGE	$T_{\mbox{\scriptsize A}} \leq 25^{\circ}\mbox{\scriptsize C}$ POWER RATING	DERATING FACTOR ABOVE T _A = 25°C	T _A = 85°C POWER RATING	T _A = 125°C POWER RATING
JG	1050 mW	8.4 mW/°C	546 mW	210 mW
FK	1375 mW	11.0 mW/°C	715 mW	275 mW
Р	1000 mW	8.0 mW/°C	520 mW	N/A



LOW-NOISE HIGH-SPEED PRECISION OPERATIONAL-AMPLIFIER

SLOS100C - FEBRUARY 1989 - REVISED SEPTEMBER 2000

recommended operating conditions

		OP2	7A, OP3	7A	OP2	OP27C, OP37C		UNIT
		MIN	NOM	MAX	MIN	NOM	MAX	UNIT
Supply voltage, V _{CC+}		4	15	22	4	15	22	V
Supply voltage, V _{CC} -		-4	-15	-22	-4	-15	-22	V
Common mode input voltage Vie	$V_{CC\pm} = \pm 15 \text{ V}, T_A = 25^{\circ}\text{C}$	± 11			±11			V
Common-mode input voltage, V _{IC}	$V_{CC\pm} = \pm 15 \text{ V}, T_A = -55^{\circ}\text{C to } 125^{\circ}\text{C}$	±10.3			±10.2			V
Operating free-air temperature, TA		-55		125	-55		125	°C

electrical characteristics at specified free-air temperature, $V_{CC\pm}$ = ± 15 V (unless otherwise noted)

	DADAMETED	TEST OF	NDITIONS	_ +	OP:	27A, OP3	7A	OP:	27C, OP3	7C	UNIT
	PARAMETER	IESI CC	ONDITIONS	T _A †	MIN	TYP	MAX	MIN	TYP	MAX	UNII
VIO	Input offset voltage	V _O = 0,	VIC = 0	25°C		10	25		30	100	μV
VIO	input onset voltage	$R_S = 50 \Omega$,	See Note 3	Full range			60			300	μν
ανιο	Average temperature coefficient of input offset voltage			Full range		0.2	0.6		0.4	1.8	μV/°C
	Long-term drift of input offset voltage	See Note 4				0.2	1		0.4	2	μV/mo
lio	Input offset current	$V_{O} = 0$,	V _{IC} = 0	25°C		7	35		12	75	nA
10	input onset current	VO = 0,	VIC - 0	Full range			50			135	ПА
I _{IB}	Input bias current	V _O = 0,	VIC = 0	25°C		±10	±40		±15	±80	nA
чь	input bias carrent	VO = 0,	VIC - 0	Full range			±60			±150	11/ (
\/\.op	Common-mode input			25°C	11 to –11			11 to –11			V
VICR	voltage range			Full range	10.3 to -10.3			10.5 to -10.5			V
		$R_L \ge 2 k\Omega$			±12	±13.8		±11.5	±13.5		
Vом	Peak output voltage swing	$R_L \ge 0.6 \text{ k}\Omega$			±10	±11.5		±10	±11.5		V
		$R_L \ge 2 \ k\Omega$		Full range	±11.5			10.5			
		$R_L \ge 2 k\Omega$,	$V_0 = \pm 10 \text{ V}$		1000	1800		700	1500		
	Large-signal differential	$R_L \ge 1 \ k\Omega$,	$V_0 = \pm 10 \text{ V}$		800	1500			1500		
AVD	voltage amplification	$R_L \ge 0.6 \text{ k}\Omega$ $V_{CC\pm} = \pm 4$	$V_{O} = \pm 1 V$		250	700		200	500		V/mV
		$R_L \ge 2 k\Omega$,	$V_0 = \pm 10 \text{ V}$	Full range	600			300			
ri(CM)	Common-mode input resistance					3			2		GΩ
r _O	Output resistance	$V_{O} = 0$,	IO = 0	25°C		70			70		Ω
CMRR	Common-mode rejection	$V_{IC} = \pm 11 \text{ V}$		25°C	114	126		100	120		dB
Jivii (i)	ratio	V _{IC} = ±10 V	/	Full range	110			94			QD.
k _{SVR}	Supply voltage rejection	$V_{CC\pm} = \pm 4$		25°C	100	120		94	118		dB
+ F. II	ratio	$V_{CC\pm} = \pm 4$	5 V to ±18 V	Full range	96			86			

[†] Full range is – 55°C to 125°C.

NOTES: 3. Input offset voltage measurements are performed by automatic test equipment approximately 0.5 seconds after applying power.

^{4.} Long-term drift of input offset voltage refers to the average trend line of offset voltage versus time over extended periods after the first 30 days of operation. Excluding the initial hour of operation, changes in V_{IO} during the first 30 days are typically 2.5 μ V (see Figure 3).



recommended operating conditions

	MIN	NOM	MAX	UNIT
Supply voltage, V _{CC+}	4	15	22	V
Supply voltage, V _{CC} _	-4	-15	-22	V
$V_{CC\pm} = \pm 15 \text{ V}, T_{A} = 25^{\circ}\text{C}$	±11			V
Common-mode input voltage, V_{IC} $V_{CC\pm} = \pm 15 \text{ V}, \qquad T_{A} = -55^{\circ}\text{C to } 125^{\circ}\text{C}$	±10.5			V
Operating free-air temperature, T _A	-25		85	°C

electrical characteristics at specified free-air temperature, $V_{CC\pm}$ = ± 15 V (unless otherwise noted)

PARAMETER		TEST CONDITIONS		- +	OP	27E, OP3	7E	OP2	OP27G, OP37G		
	PARAMETER	IESI CC	SNOTTIONS	T _A †	MIN	TYP	MAX	MIN	TYP	MAX	UNIT
\/10	Input offset voltage	$V_0 = 0,$	V _{IC} = 0	25°C		10	25		30	100	μV
VIO	input onset voltage	$R_S = 50 \Omega$,	See Note 3	Full range			60			220	μν
αVIO	Average temperature coefficient of input offset voltage			Full range		0.2	0.6		0.4	1.8	μV/°C
	Long-term drift of input offset voltage	See Note 4				0.2	1		0.4	2	μV/mo
lio	Input offset current	$V_{O} = 0$,	\/10 = 0	25°C		7	35		12	75	nA
110	input onset current	VO = 0,	VIC = 0	Full range			50			135	ША
I _{IB}	Input bias current	$V_{O} = 0$,	\/10 = 0	25°C		±10	±40		±15	±80	nA
'IB	mpat blad darrent	10 - 0,	VIC - 0	Full range			±60			±150	117 (
VICR	Common-mode input			25°C	11 to –11			11 to –11			V
IOIX	voltage range			Full range	10.3 to -10.3			10.5 to -10.5			
	Dools output voltogo	$R_L \ge 2 k\Omega$			±12	±13.8		±11.5	±13.5		
VOМ	Peak output voltage swing	$R_L \ge 0.6 \text{ k}\Omega$			±10	±11.5		±10	±11.5		V
		$R_L \ge 2 k\Omega$		Full range	±11.5			10.5			
			$V_0 = \pm 10 \text{ V}$		1000	1800		700	1500		
	Large-signal differential		$V_0 = \pm 10 \text{ V}$		800	1500			1500		
AVD	voltage amplification	$R_L \ge 0.6 \text{ k}\Omega$ $V_{CC\pm} = \pm 4$	$V_{O} = \pm 1 V,$		250	700		200	500		V/mV
		$R_L \ge 2 k\Omega$,	$V_0 = \pm 10 \text{ V}$	Full range	600			450			
ri(CM)	Common-mode input resistance					3			2		GΩ
r _o	Output resistance	$V_{O} = 0$,	I _O = 0	25°C		70			70		Ω
CMRR	Common-mode rejection	V _{IC} = ±11 V		25°C	114	126		100	120		dB
	ratio	V _{IC} = ±10 V		Full range	110			96			
ksvr	Supply voltage rejection ratio	$V_{CC\pm}=\pm 4$		25°C	100	120		94	118		dB
+ = "	ratio	$V_{CC\pm} = \pm 4$.5 V to ±18 V	Full range	96			90			

[†] Full range is – 25°C to 85°C.

NOTES: 3. Input offset voltage measurements are performed by automatic test equipment approximately 0.5 seconds after applying power.

Long-term drift of input offset voltage refers to the average trend line of offset voltage versus time over extended periods after the
first 30 days of operation. Excluding the initial hour of operation, changes in V_{IO} during the first 30 days are typically 2.5 μV
(see Figure 3).



OP27 operating characteristics over operating free-air temperature range, $V_{CC\pm}$ = $\pm 15~V$

PARAMETER		TEST CONI	OITIONS	OP2	7A, OP2	?7E	OP2	UNIT		
	PARAIVIETER	TEST CON	DITIONS	MIN	TYP	MAX	MIN	TYP	MAX	UNIT
SR	Slew rate	$A_{VD} \ge 1$,	$R_L \ge 2 \ k\Omega$	1.7	2.8		1.7	2.8		V/μs
V _{N(PP)}	Peak-to-peak equivalent input noise voltage	f = 0.1 Hz to 10 Hz, See Figure 34	$R_S = 20 \Omega$,		0.08	0.18		0.09	0.25	μV
		f = 10 Hz,	R _S = 20 Ω		3.5	5.5		3.8	8	
Vn	Equivalent input noise voltage	f = 30 Hz,	$R_S = 20 \Omega$		3.1	4.5		3.3	5.6	nV/√ Hz
		f = 1 kHz,	$R_S = 20 \Omega$		3	3.8		3.2	4.5	
		f = 10 Hz,	See Figure 35		1.5	4		1.5		
In	Equivalent input noise current	f = 30 Hz,	See Figure 35		1	2.3		1		pA/√ Hz
		f = 1 kHz,	See Figure 35		0.4	0.6		0.4	0.6	
	Gain-bandwidth product	f = 100 kHz		5	8	·	5	8		MHz

OP37 operating characteristics over operating free-air temperature range, $V_{CC\pm}$ = $\pm 15~V$

	PARAMETER	TEST CON	TEST CONDITIONS		37A, OP	37E	OP3	UNIT		
	PARAIVIETER	TEST CON	DITIONS	MIN	TYP	MAX	MIN	TYP	MAX	UNIT
SR	Slew rate	$A_{VD} \ge 5$,	$R_L \ge 2 k\Omega$	11	17		11	17		V/μs
V _{N(PP)}	Peak-to-peak equivalent input noise voltage	f = 0.1 Hz to 10 Hz, See Figure 34	$R_S = 20 \Omega$,		0.08	0.18		0.09	0.25	μV
		f = 10 Hz,	R _S = 20 Ω		3.5	5.5		3.8	8	
٧n	Equivalent input noise voltage	f = 30 Hz,	$R_S = 20 \Omega$		3.1	4.5		3.3	5.6	nV/√ Hz
	voltage	f = 1 kHz,	$R_S = 20 \Omega$		3	3.8		3.2	4.5]
		f = 10 Hz,	See Figure 35		1.5	4		1.5		
In	Equivalent input noise current	f = 30 Hz,	See Figure 35		1	2.3		1		pA/√Hz
		f = 1 kHz,	See Figure 35		0.4	0.6		0.4	0.6]
	Cain handwidth aradust	f = 10 kHz		45	63		45	63		NAL I-
	Gain-bandwidth product	$A_V \ge 5$,	f = 1 MHz		40			40		MHz

TYPICAL CHARACTERISTICS

Table of Graphs

			FIGURE
VIO	Input offset voltage	vs Temperature	1
ΔVΙΟ	Change in input offset voltage	vs Time after power on vs Time (long-term drift)	2 3
lιΟ	Input offset current	vs Temperature	4
I _{IB}	Input bias current	vs Temperature	5
VICR	Common-mode input voltage range	vs Supply voltage	6
V _{OM}	Maximum peak output voltage	vs Load resistance	7
V _{O(PP)}	Maximum peak-to-peak output voltage	vs Frequency	8, 9
AVD	Differential voltage amplification	vs Supply voltage vs Load resistance vs Frequency	10 11 12, 13, 14
CMRR	Common-mode rejection ratio	vs Frequency	15
ksvr	Supply voltage rejection ratio	vs Frequency	16
SR	Slew rate	vs Temperature vs Supply voltage vs Load resistance	17 18 19
фm	Phase margin	vs Temperature	20, 21
ф	Phase shift	vs Frequency	12, 13
V _n	Equivalent input noise voltage	vs Bandwidth vs Source resistance vs Supply voltage vs Temperature vs Frequency	22 23 24 25 26
In	Equivalent input noise current	vs Frequency	27
	Gain-bandwidth product	vs Temperature	20, 21
los	Short-circuit output current	vs Time	28
Icc	Supply current	vs Supply voltage	29
	Pulse response	Small signal Large signal	30, 32 31, 33



Figure 1

TYPICAL CHARACTERISTICS†

INPUT OFFSET VOLTAGE OF WARM-UP CHANGE IN REPRESENTATIVE INDIVIDUAL UNITS **INPUT OFFSET VOLTAGE** FREE-AIR TEMPERATURE **ELAPSED TIME** 100 $V_{CC\pm} = \pm 15 \text{ V}$ $V_{CC\pm} = \pm 15 V$ 80 $T_A = 25^{\circ}C$ $^{\Delta}$ V $_{10}$ – Change in Input Offset Voltage – μ V OP27C/37C 10 60 V_{IO} – Input Offset Voltage – μV OP27CP/GP OP27A/37A 40 OP37CP/GP OP27A/37A 20 0 OP27E/37E - 20 5 - 40 OP27G/37G OP27AP/EP OP37AP/EP OP27C/37C - 60 -80- 100 - 50 - 25 25 50 75 100 125 5 TA - Free-Air Temperature - °C Time After Power On - minutes

LONG-TERM DRIFT OF INPUT OFFSET VOLTAGE OF REPRESENTATIVE INDIVIDUAL UNITS

Figure 2

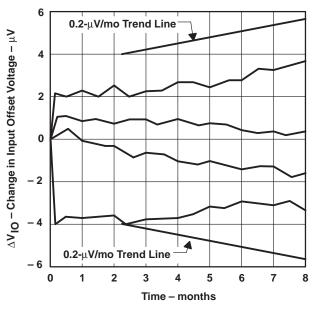


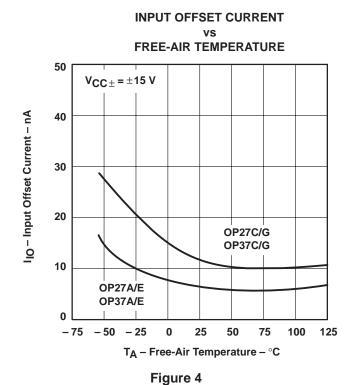
Figure 3

[†] Data for temperatures below - 25°C and above 85°C are applicable to the OP27A, OP27C, OP37A, and OP37C only.



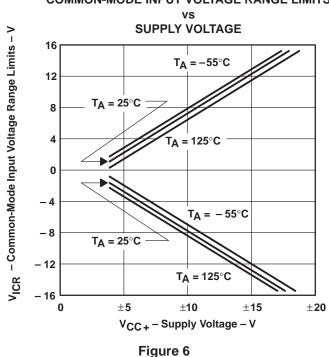
INPUT BIAS CURRENT

TYPICAL CHARACTERISTICS[†]



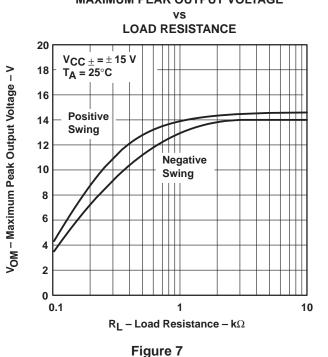
FREE-AIR TEMPERATURE $\pm\, 50$ $V_{CC\pm} = \pm 15 V$ \pm 40 IlB - Input Bias Current - nA $\pm\,30$ OP27C/G $\pm\,20$ OP37C/G ± 10 OP27A/E OP37A/E -75 -50 -2525 50 75 100 125 T_A - Free-Air Temperature - °C

COMMON-MODE INPUT VOLTAGE RANGE LIMITS



MAXIMUM PEAK OUTPUT VOLTAGE

Figure 5



† Data for temperatures below - 25°C and above 85°C are applicable to the OP27A, OP27C, OP37A, and OP37C only.



TYPICAL CHARACTERISTICS

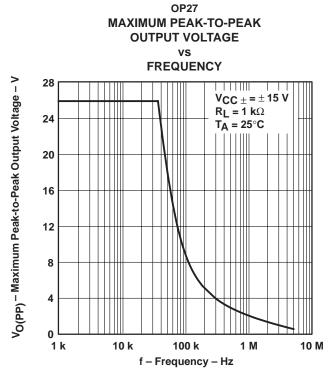


Figure 8

OP27A, OP27E, OP37A, OP37E LARGE-SIGNAL DIFFERENTIAL VOLTAGE AMPLIFICATION VS

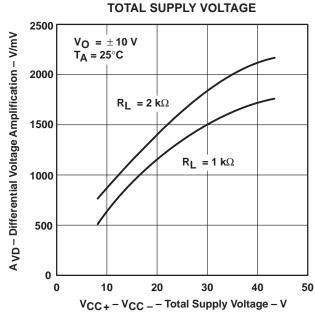


Figure 10

OP37 MAXIMUM PEAK-TO-PEAK OUTPUT VOLTAGE VS

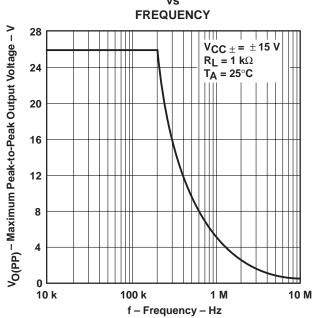


Figure 9

OP27A, OP27E, OP37A, OP37E LARGE-SIGNAL DIFFERENTIAL VOLTAGE AMPLIFICATION VS

LOAD RESISTANCE

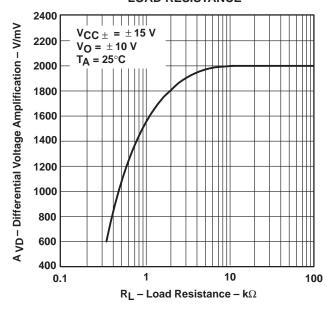
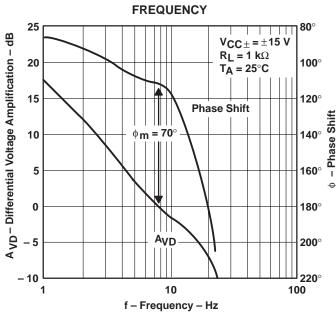


Figure 11



TYPICAL CHARACTERISTICS

OP27 LARGE-SIGNAL DIFFERENTIAL VOLTAGE AMPLIFICATION AND PHASE SHIFT



OP37
LARGE-SIGNAL DIFFERENTIAL
VOLTAGE AMPLIFICATION AND PHASE SHIFT

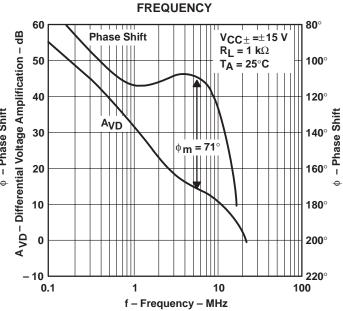


Figure 12

OP27A, OP27E, OP37A, OP37E LARGE-SIGNAL

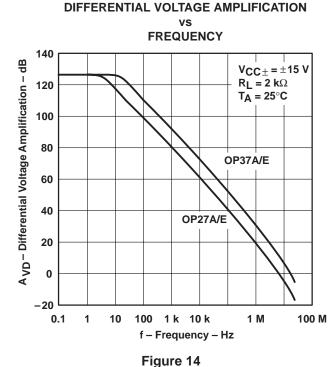
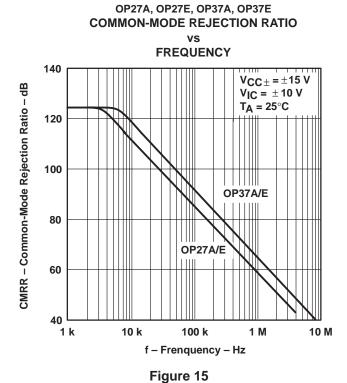


Figure 13





TYPICAL CHARACTERISTICS[†]

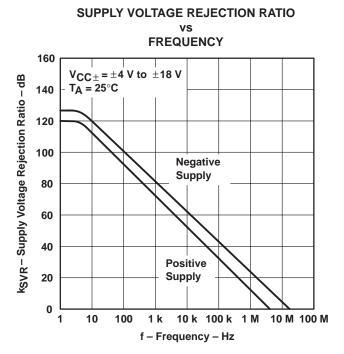
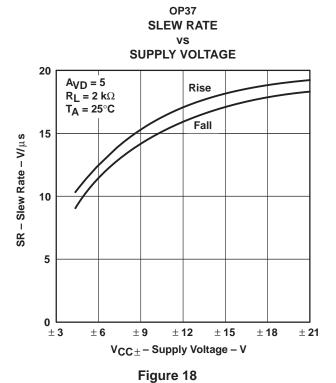


Figure 16



SLEW RATE vs FREE-AIR TEMPERATURE

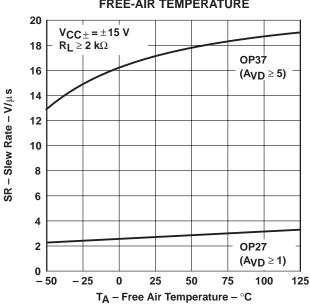
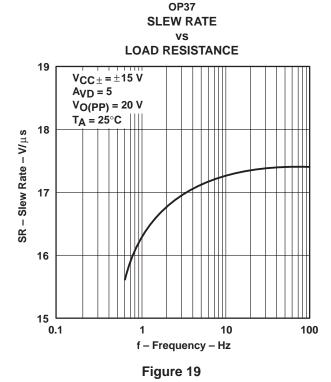


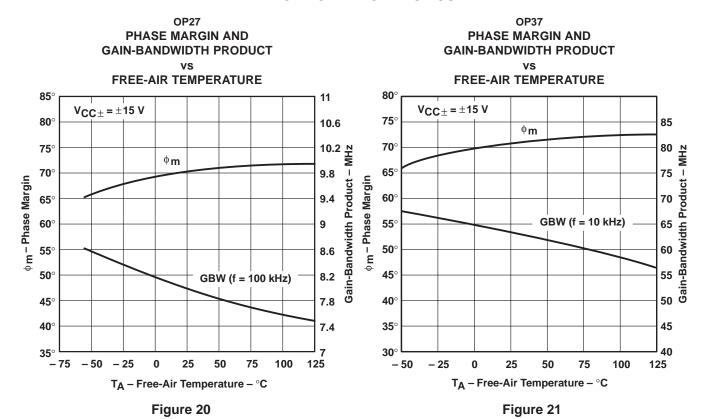
Figure 17



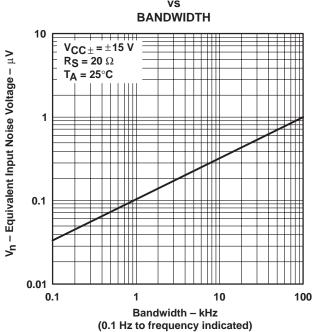
 † Data for temperatures below -25°C and above 85 $^\circ\text{C}$ are applicable to the OP27A, OP27C, OP37A, and OP37C only.



TYPICAL CHARACTERISTICS[†]



EQUIVALENT INPUT NOISE VOLTAGE vs



TOTAL EQUIVALENT INPUT NOISE VOLTAGE

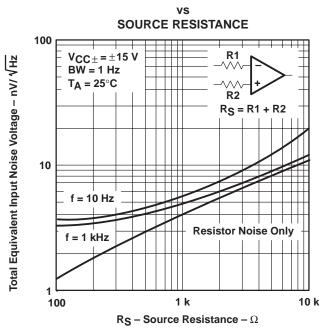


Figure 22 Figure 23

† Data for temperatures below - 25°C and above 85°C are applicable to the OP27A, OP27C, OP37A, and OP37C only.

TEXAS INSTRUMENTS
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TYPICAL CHARACTERISTICS†

OP27A, OP27E, OP37A, OP37E EQUIVALENT INPUT NOISE VOLTAGE VS

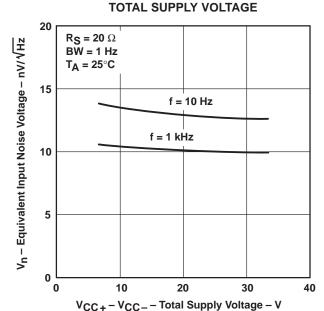


Figure 24

EQUIVALENT INPUT NOISE VOLTAGE vs FREE-AIR TEMPERATURE

OP27A, OP27E, OP37A, OP37E

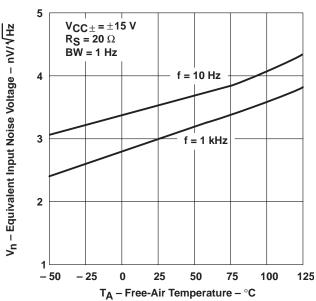


Figure 25

OP27A, OP27E, OP37A, OP37E EQUIVALENT INPUT NOISE VOLTAGE VS

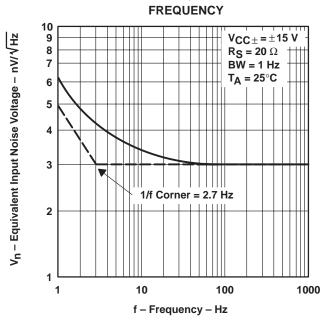


Figure 26

EQUIVALENT INPUT NOISE CURRENT

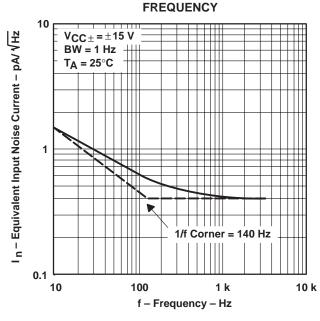


Figure 27

[†] Data for temperatures below - 25°C and above 85°C are applicable to the OP27A, OP27C, OP37A, and OP37C only.



TYPICAL CHARACTERISTICS†

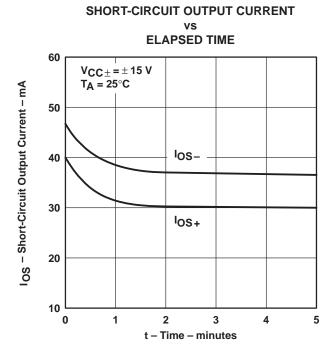


Figure 28

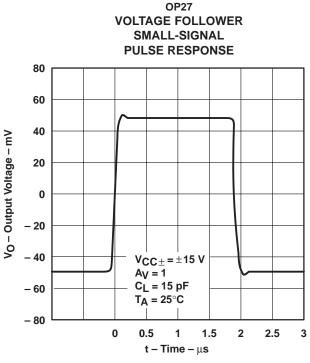


Figure 30

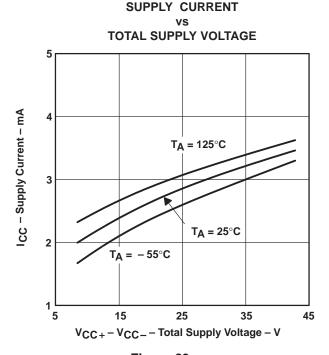
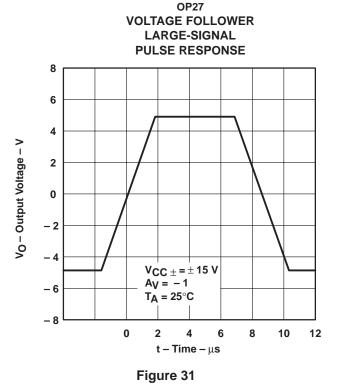


Figure 29



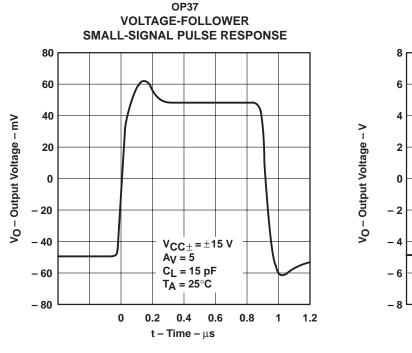
† Data for temperatures below - 25°C and above 85°C are applicable to the OP27A, OP27C, OP37A, and OP37C only.

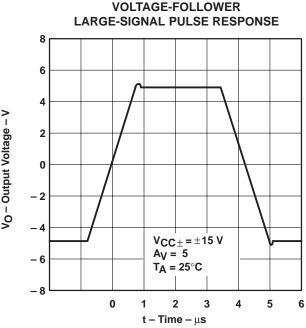


LOW-NOISE HIGH-SPEED PRECISION OPERATIONAL-AMPLIFIER

SLOS100C - FEBRUARY 1989 - REVISED SEPTEMBER 2000

TYPICAL CHARACTERISTICS





OP37

Figure 32

Figure 33

APPLICATION INFORMATION

general

The OP27 and OP37 series devices can be inserted directly onto OP07, OP05, μ A725, and SE5534 sockets with or without removing external compensation or nulling components. In addition, the OP27 and OP37 can be fitted to μ A741 sockets by removing or modifying external nulling components.

noise testing

Figure 34 shows a test circuit for 0.1-Hz to 10-Hz peak-to-peak noise measurement of the OP27 and OP37. The frequency response of this noise tester indicates that the 0.1-Hz corner is defined by only one zero. Because the time limit acts as an additional zero to eliminate noise contributions from the frequency band below 0.1 Hz, the test time to measure 0.1-Hz to 10-Hz noise should not exceed 10 seconds.

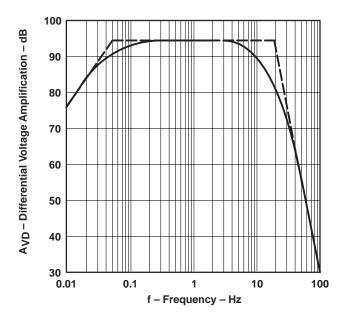
Measuring the typical 80-nV peak-to-peak noise performance of the OP27 and OP37 requires the following special test precautions:

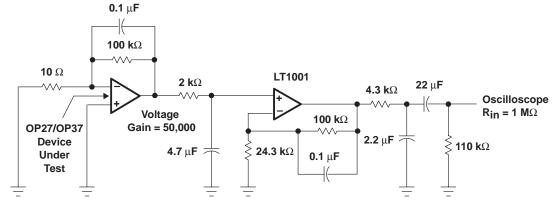
- 1. The device should be warmed up for at least five minutes. As the operational amplifier warms up, the offset voltage typically changes $4\,\mu\text{V}$ due to the chip temperature increasing from 10°C to 20°C starting from the moment the power supplies are turned on. In the 10-s measurement interval, these temperature-induced effects can easily exceed tens of nanovolts.
- 2. For similar reasons, the device should be well shielded from air currents to eliminate the possibility of thermoelectric effects in excess of a few nanovolts, which would invalidate the measurements.
- 3. Sudden motion in the vicinity of the device should be avoided, as it produces a feedthrough effect that increases observed noise.



APPLICATION INFORMATION

noise testing (continued)





NOTE: All capacitor values are for nonpolarized capacitors only.

Figure 34. 0.1-Hz to 10-Hz Peak-to-Peak Noise Test Circuit and Frequency Response

APPLICATION INFORMATION

noise testing (continued)

When measuring noise on a large number of units, a noise-voltage density test is recommended. A 10-Hz noise-voltage density measurement correlates well with a 0.1-Hz to 10-Hz peak-to-peak noise reading since both results are determined by the white noise and the location of the 1/f corner frequency.

Figure 35 shows a circuit measuring current noise and the formula for calculating current noise.

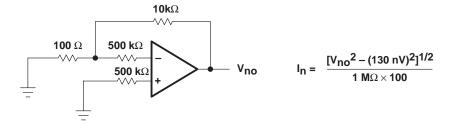


Figure 35. Current Noise Test Circuit and Formula

offset voltage adjustment

The input offset voltage and temperature coefficient of the OP27 and OP37 are permanently trimmed to a low level at wafer testing. However, if further adjustment of V_{IO} is necessary, using a 10-k Ω nulling potentiometer as shown in Figure 36 does not degrade the temperature coefficient α_{VIO} . Trimming to a value other than zero creates an α_{VIO} of $V_{IO}/300~\mu\text{V/°C}$. For example, if V_{IO} is adjusted to 300 μ V, the change in α_{VIO} is 1 μ V/°C.

The adjustment range with a 10-k Ω potentiometer is approximately ± 2.5 mV. If a smaller adjustment range is needed, the sensitivity and resolution of the nulling can be improved by using a smaller potentiometer in conjunction with fixed resistors. The example in Figure 37 has an approximate null range of $\pm 200 \,\mu\text{V}$.

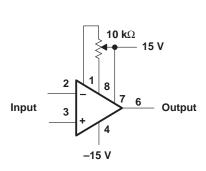


Figure 36. Standard Input Offset Voltage Adjustment

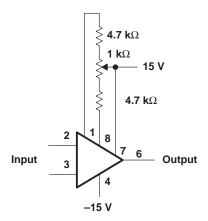


Figure 37. Input Offset Voltage Adjustment With Improved Sensitivity

offset voltage and drift

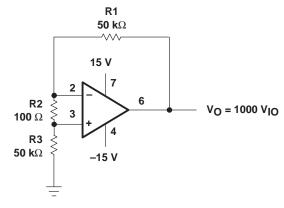
Unless proper care is exercised, thermoelectric effects caused by temperature gradients across dissimilar metals at the contacts to the input terminals can exceed the inherent temperature coefficient ${}^{\infty}V_{1O}$ of the amplifier. Air currents should be minimized, package leads should be short, and the two input leads should be close together and at the same temperature.



APPLICATION INFORMATION

offset voltage and drift (continued)

The circuit shown in Figure 38 measures offset voltage. This circuit can also be used as the burn-in configuration for the OP27 and OP37 with the supply voltage increased to 20 V, R1 = R3 = 10 k Ω , R2 = 200 Ω , and A_{VD} = 100.



NOTE A: Resistors must have low thermoelectric potential.

Figure 38. Test Circuit for Offset Voltage and Offset Voltage Temperature Coefficient

unity gain buffer applications

The resulting output waveform, when $R_f \le 100 \Omega$ and the input is driven with a fast large-signal pulse (> 1 V), is shown in the pulsed-operation diagram in Figure 39.

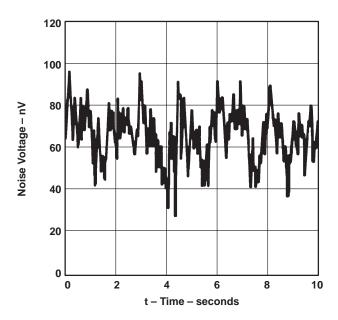


Figure 39. Pulsed Operation

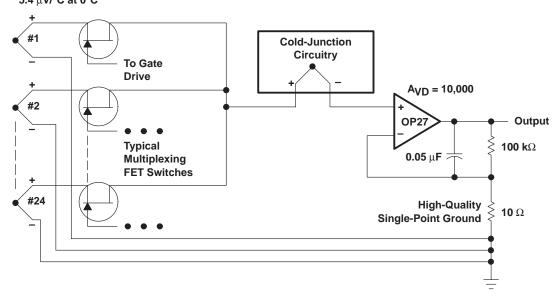
During the initial (fast-feedthrough-like) portion of the output waveform, the input protection diodes effectively short the output to the input, and a current, limited only by the output short-circuit protection, is drawn by the signal generator. When $R_f \geq 500~\Omega$, the output is capable of handling the current requirements (load current $\leq 20~\text{mA}$ at 10 V), the amplifier stays in its active mode, and a smooth transition occurs. When $R_f > 2~k\Omega$, a pole is created with R_f and the amplifier's input capacitance, creating additional phase shift and reducing the phase margin. A small capacitor (20 pF to 50 pF) in parallel with R_f eliminates this problem.

APPLICATION INFORMATION

unity gain buffer applications (continued)



Type S Thermocouples 5.4 μ V/°C at 0°C



NOTE A: If 24 channels are multiplexed per second and the output is required to settle to 0.1 % accuracy, the amplifier's bandwidth cannot be limited to less than 30 Hz. The peak-to-peak noise contribution of the OP27 will still be only 0.11 μV, which is equivalent to an error of only 0.02°C.

Figure 40. Low-Noise, Multiplexed Thermocouple Amplifier and 0.1-Hz To 10-Hz Peak-to-Peak Noise Voltage



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